
Lab 10. Speed Control of a D.C. motor

Speed Measurement:

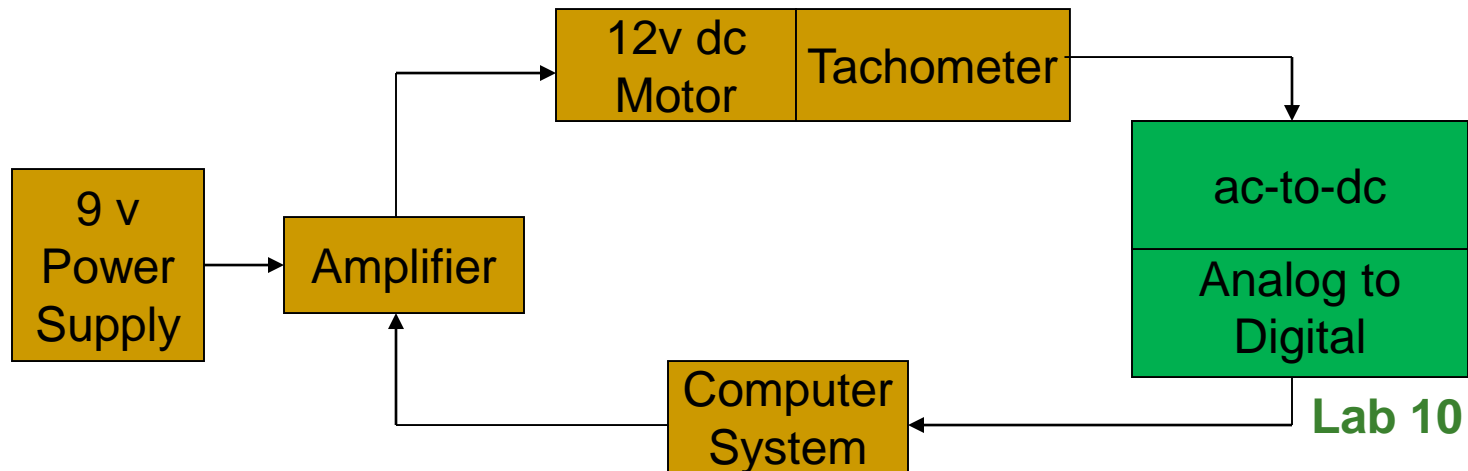
Tach Amplitude Method

References: [STM32L100 Data Sheet \(pin definitions\)](#)

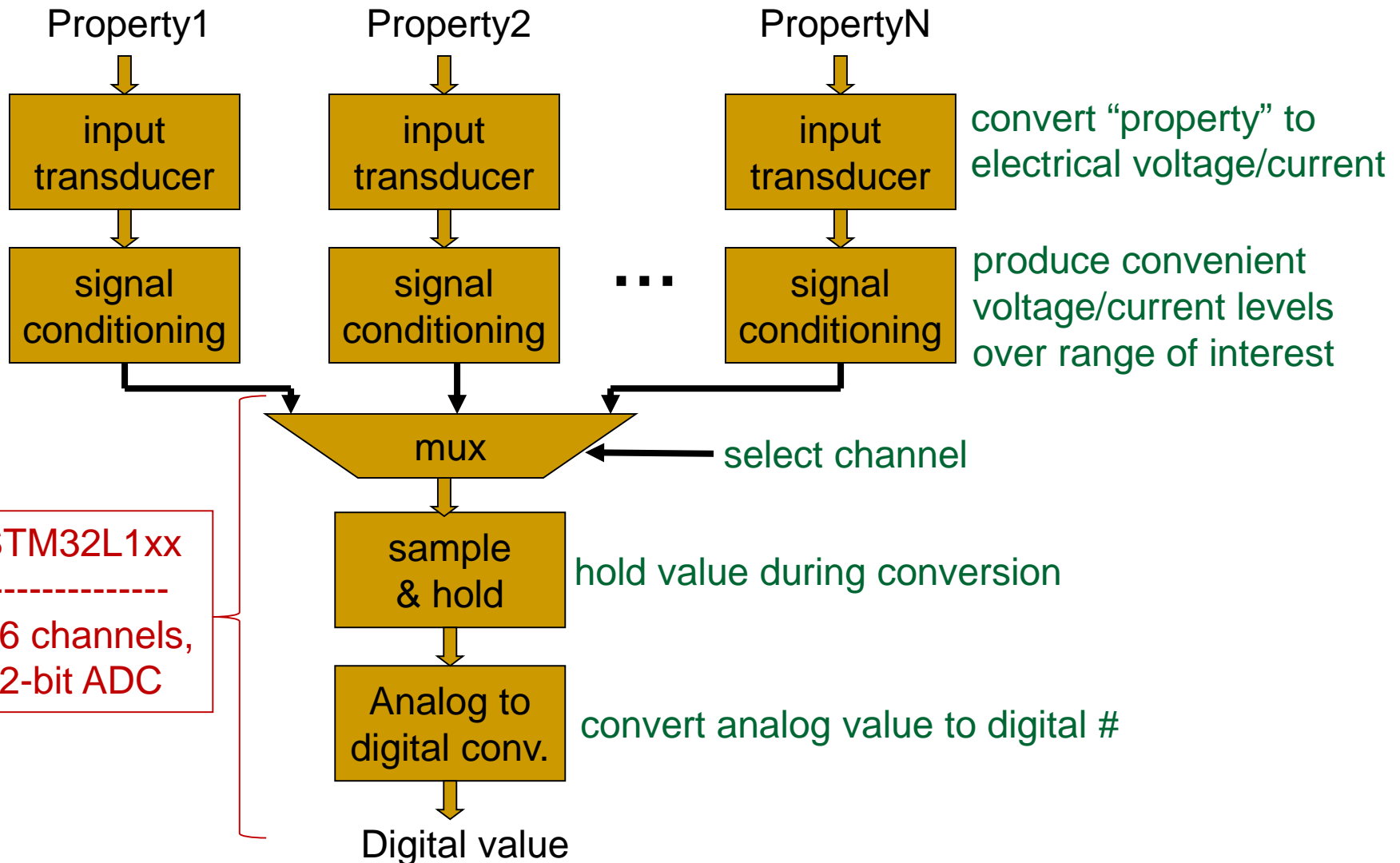
[STM32L100 Ref. Manual \(ADC, GPIO, Clocks\)](#)

Motor Speed Control Project

1. Generate PWM waveform
2. Amplify the waveform to drive the motor
3. Measure motor speed
4. Measure motor parameters
5. Control speed with a PID controller



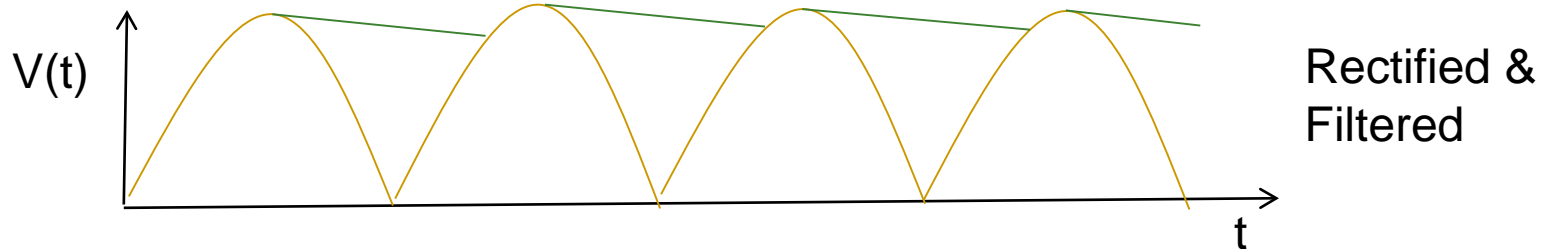
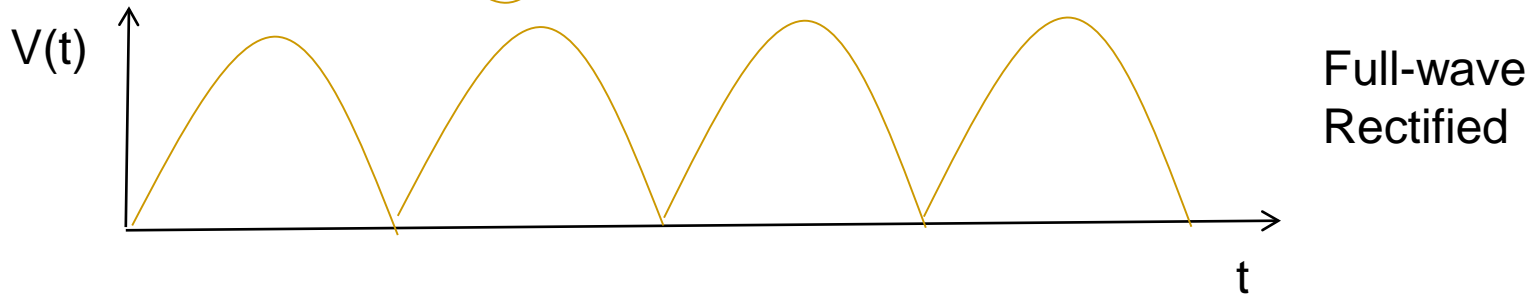
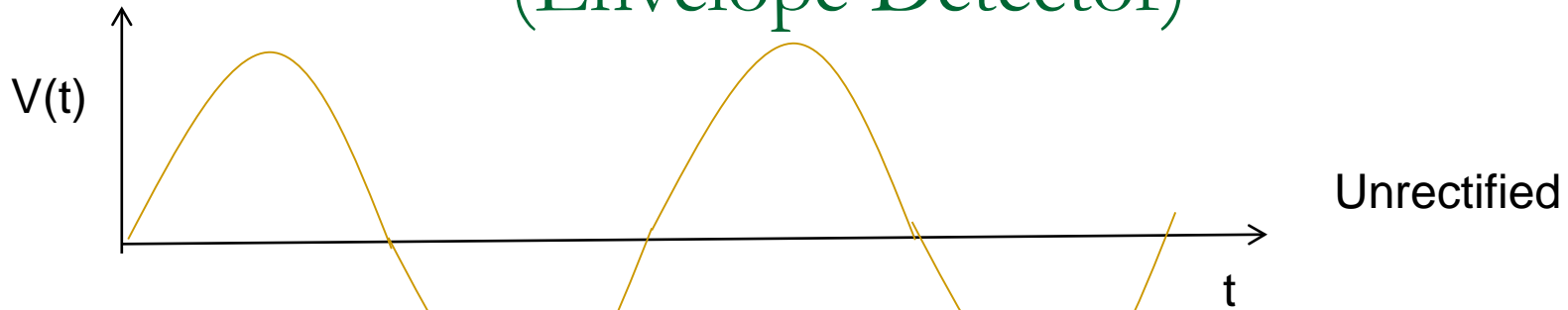
Typical analog input subsystem



Signal conditioning

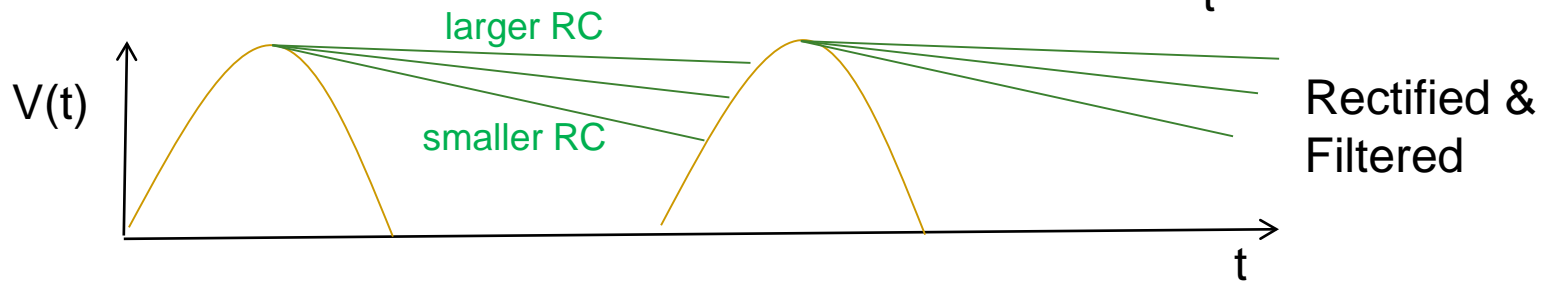
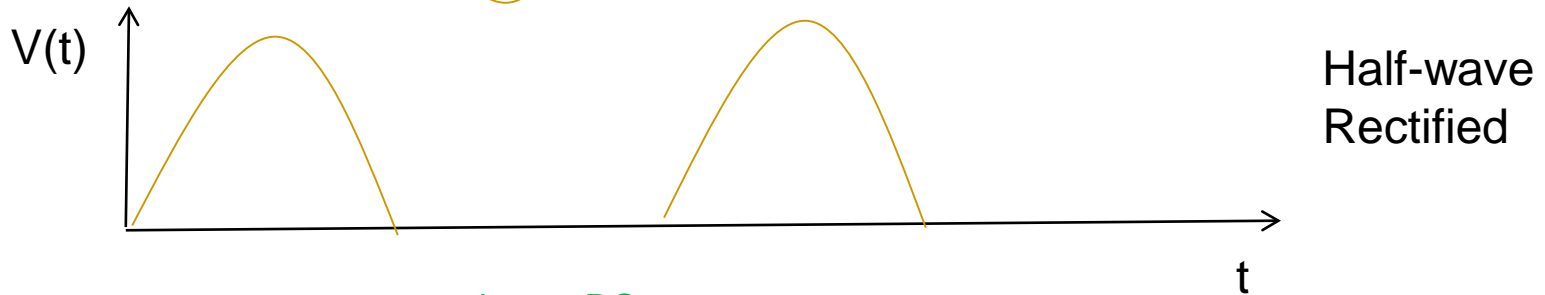
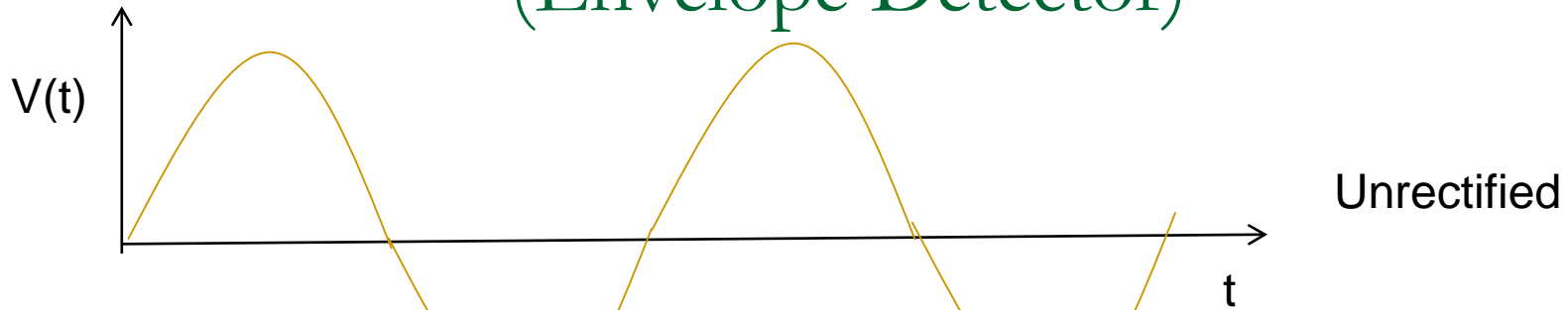
- Produce noise-free signal over A/D converter input range STM32L100-Discovery : [0v to 3v]
 - **Convert AC signal to DC form**
 - *Needed in this lab to measure tachometer signal amplitude*
 - **Amplify/attenuate voltage/current levels**
 - *Tachometer voltage might be > max ADC input range*
 - Bias (shift levels to desired range)
 - Filter to remove noise
 - Common mode rejection for differential signals
 - Isolation/protection (optical/transformer)
-

Example: AC to DC conversion (Envelope Detector)

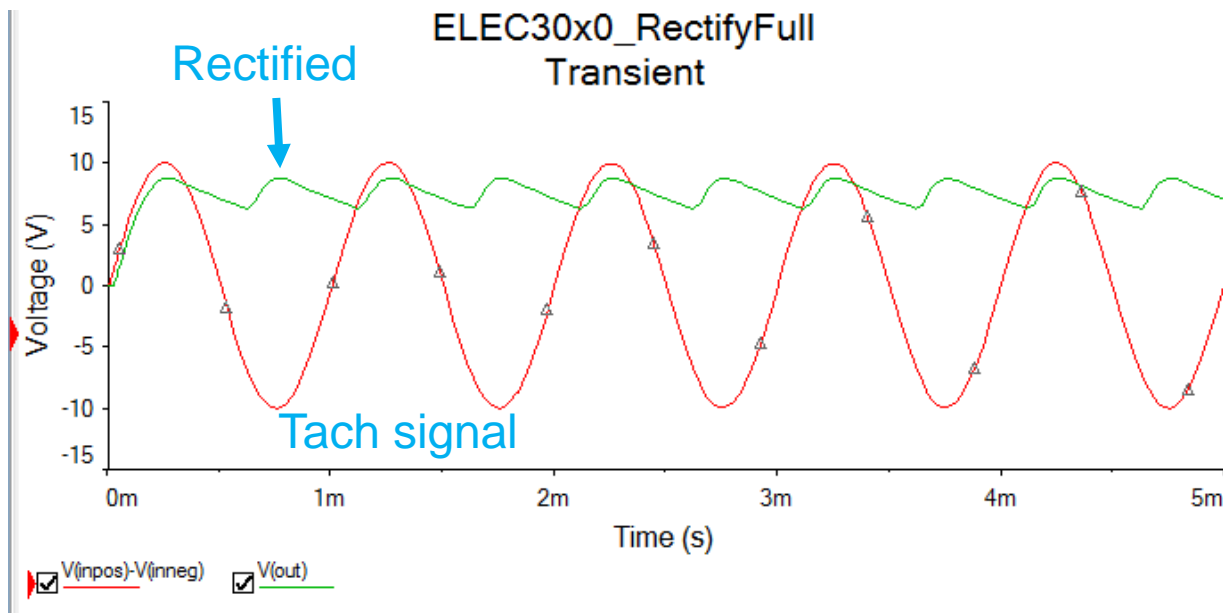
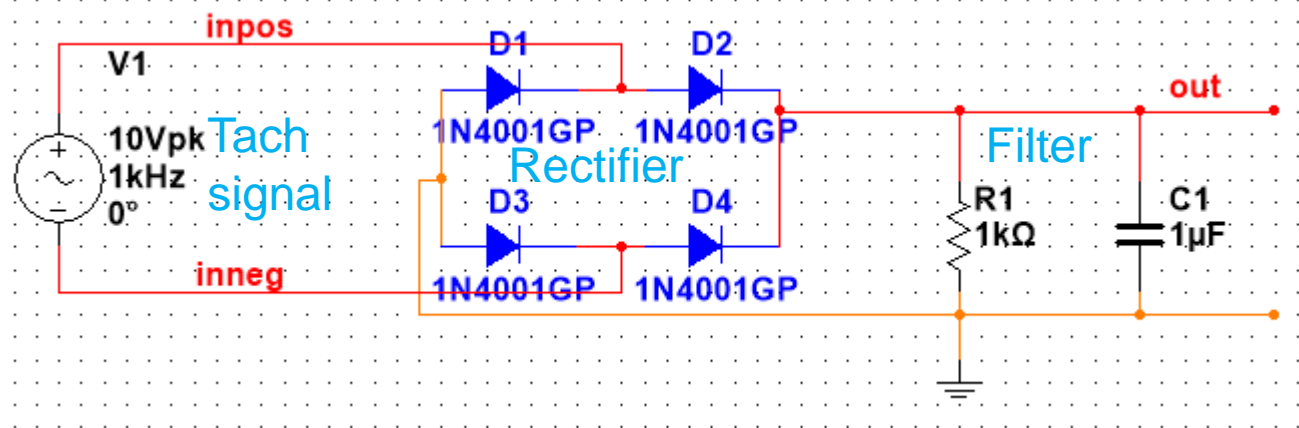


(May also choose half-wave rectified form – consider “ripple” in DC level)

Example: AC to DC conversion (Envelope Detector)



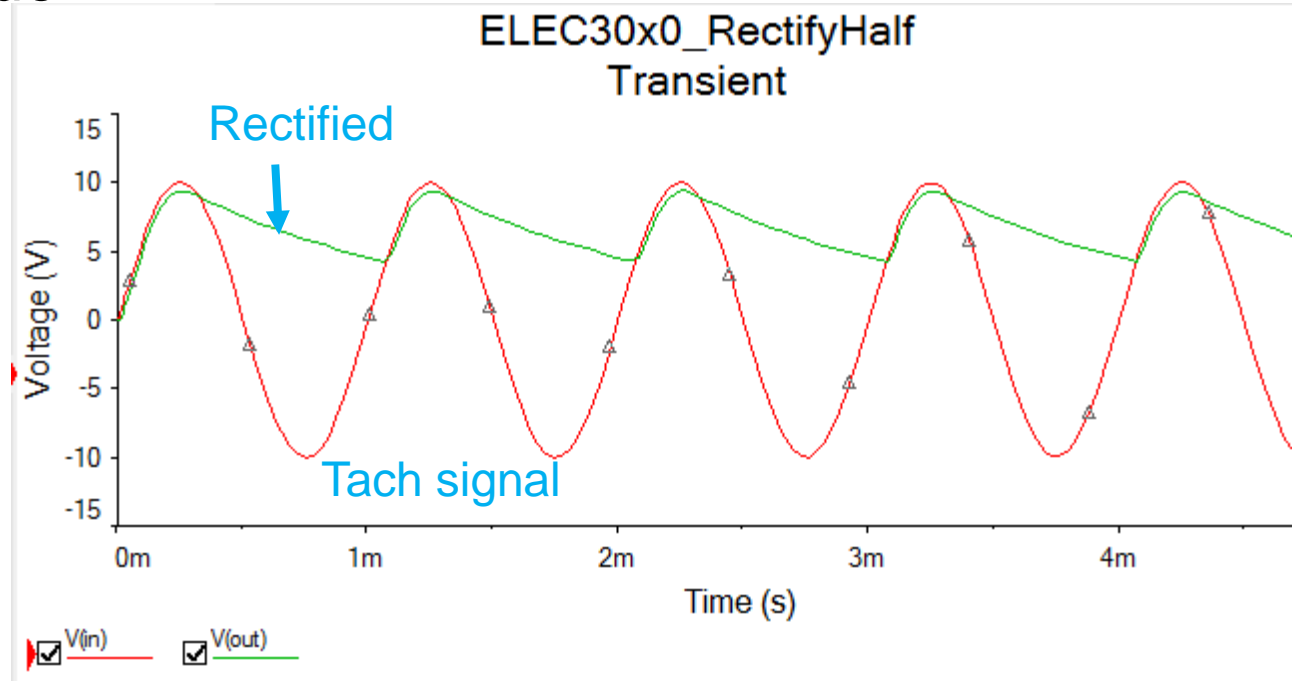
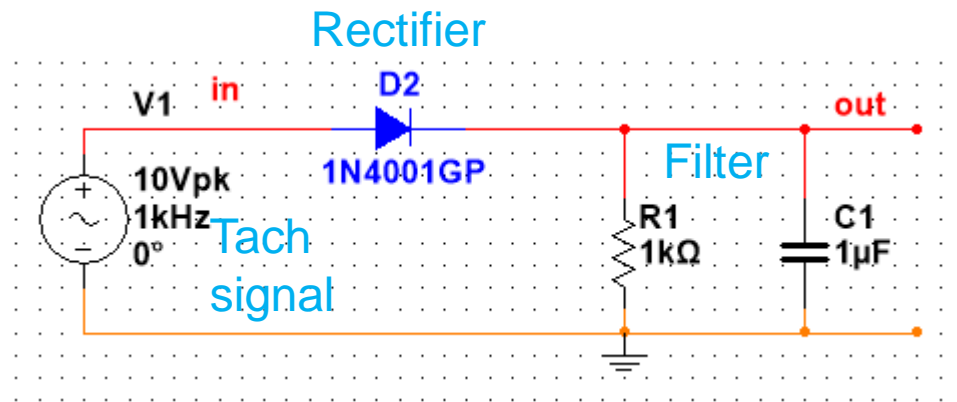
Signal conditioning to measure tach signal amplitude



Rectified signal:
Is output "ripple" acceptable?

Is the DC level acceptable?

Signal conditioning to measure tach signal amplitude



Rectified signal:
Is output "ripple" acceptable?

Is the DC level acceptable?

Analog to digital conversion

- Given: continuous-time electrical signal

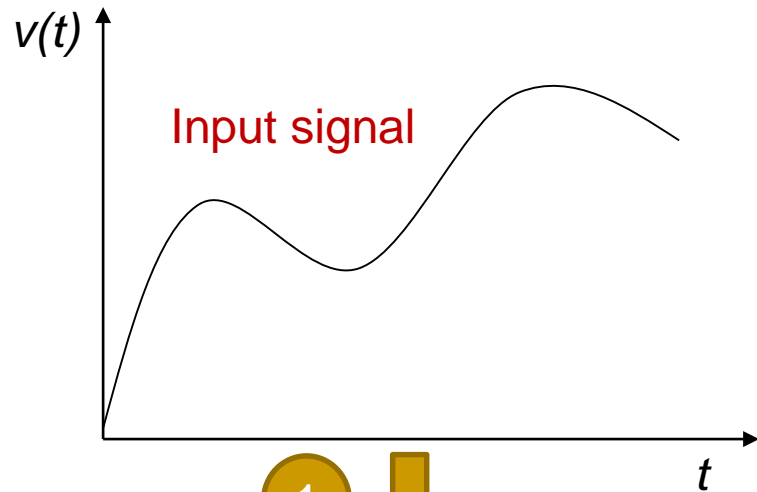
$$v(t), t \geq 0$$

- Desired: sequence of discrete numeric values that represent the signal at selected sampling times :

$$v(0), v(T), v(2T), \dots, v(nT)$$

- $v(nT) = v(t)$ value measured at the n^{th} sample time
 - Quantized to one of 2^k discrete levels
 - Produces a k -bit number
- $T = \text{"sampling time"}$
 - $v(t)$ is "sampled" every T seconds
 - Sampling frequency $F_{\text{sample}} = 1/T$

A/D conversion process

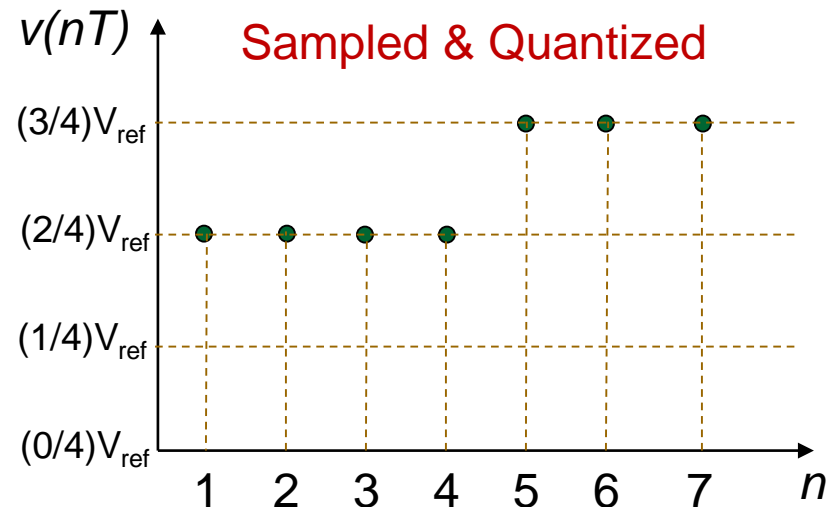
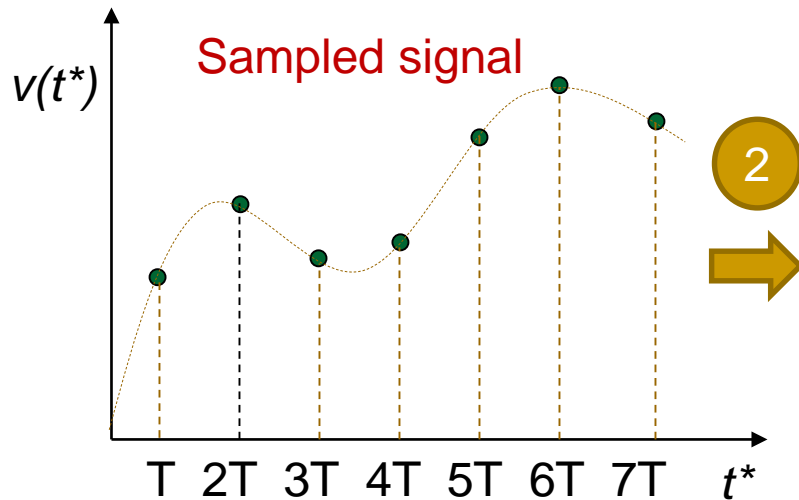


Sampled data sequence:

$n=1$ 2 3 4 5 6 7
 $d=10, 10, 10, 10, 11, 11, 11$

binary data

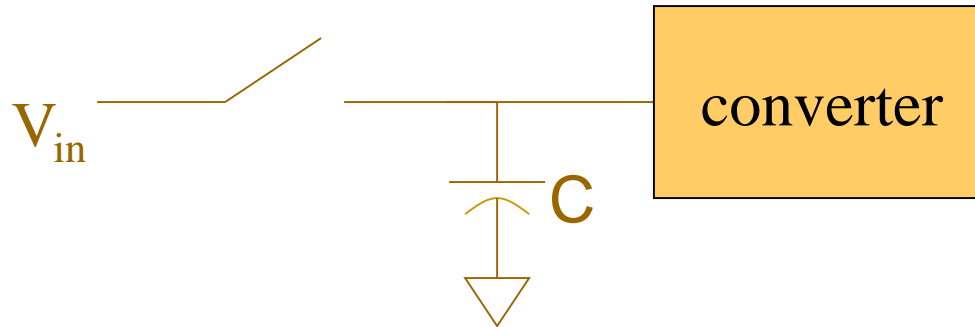
$$v(nT) = (d/4)V_{\text{ref}}$$



A/D conversion parameters

- Sampling rate, F (sampling interval $T = 1/F$)
 - *Nyquist rate* $\geq 2 \times$ (highest frequency in the signal)
 - to reproduce sampled signals
 - CD-quality music sampled at 44.1KHz (ear can hear up to about 20-22KHz)
 - Voice in digital telephone sampled at 8KHz
- Precision (# bits in sample value)
 - $k = \#$ of bits used to represent sample values
 - “precision” = step size between values = $(1/2^k) \times V_{\text{range}}$
Ex. Temperatures $[-20^{\circ}\text{C} \dots +60^{\circ}\text{C}]$:
If $k=8$, precision = $80^{\circ}\text{C}/256 = 0.3125^{\circ}\text{C}$
- Accuracy = degree to which converter discerns proper level (error when rounding to nearest level)

Sample-and-hold



- Required if A/D conversion is slow relative to frequency of signal:
 - Close switch to “sample” V_{in} (charge capacitor C to V_{in})
 - Aperture (sampling) time = duration of switch closure
 - Open switch to “hold” V_{in} on C
 - Sample time often programmable.

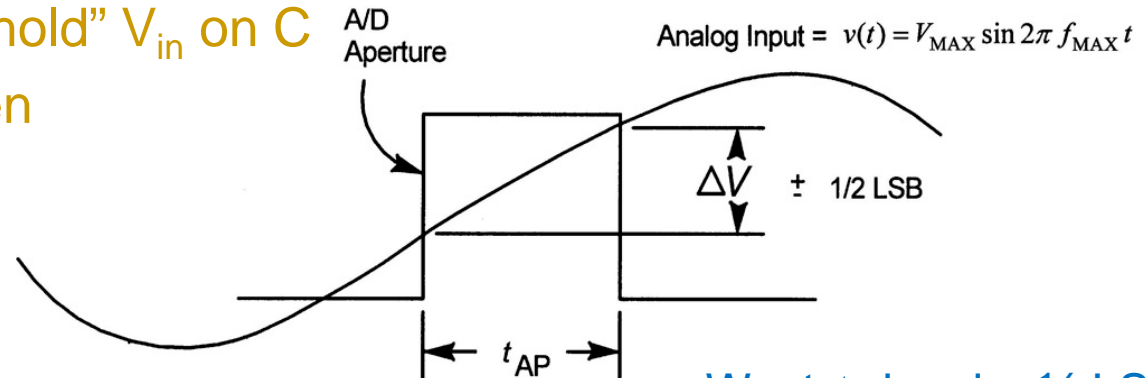


Figure 17-4 Aperture time error.

Want $\Delta \text{signal} < \frac{1}{2} \text{LSB}$

Digital to analog conversion

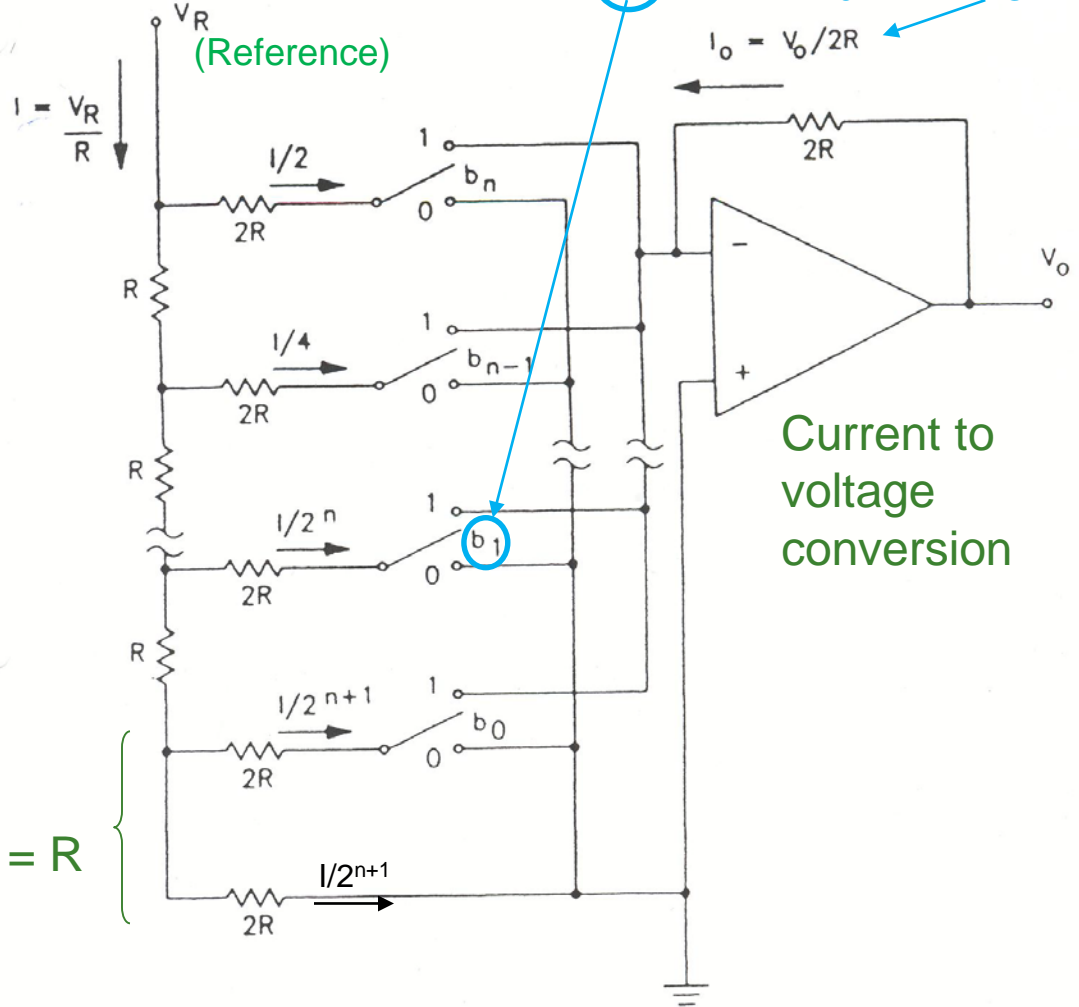
$$\text{Number} = b_n b_{n-1} \dots b_1 b_0 = b_n * 2^n + b_{n-1} * 2^{n-1} + \dots + b_1 * 2^1 + b_0 * 2^0 = I_o$$

R-2R Ladder Network

$$V_o = V_R \sum_{k=0}^n b_k \left(\frac{1}{2^k} \right)$$

Equivalent resistance = R

Equivalent resistance = R

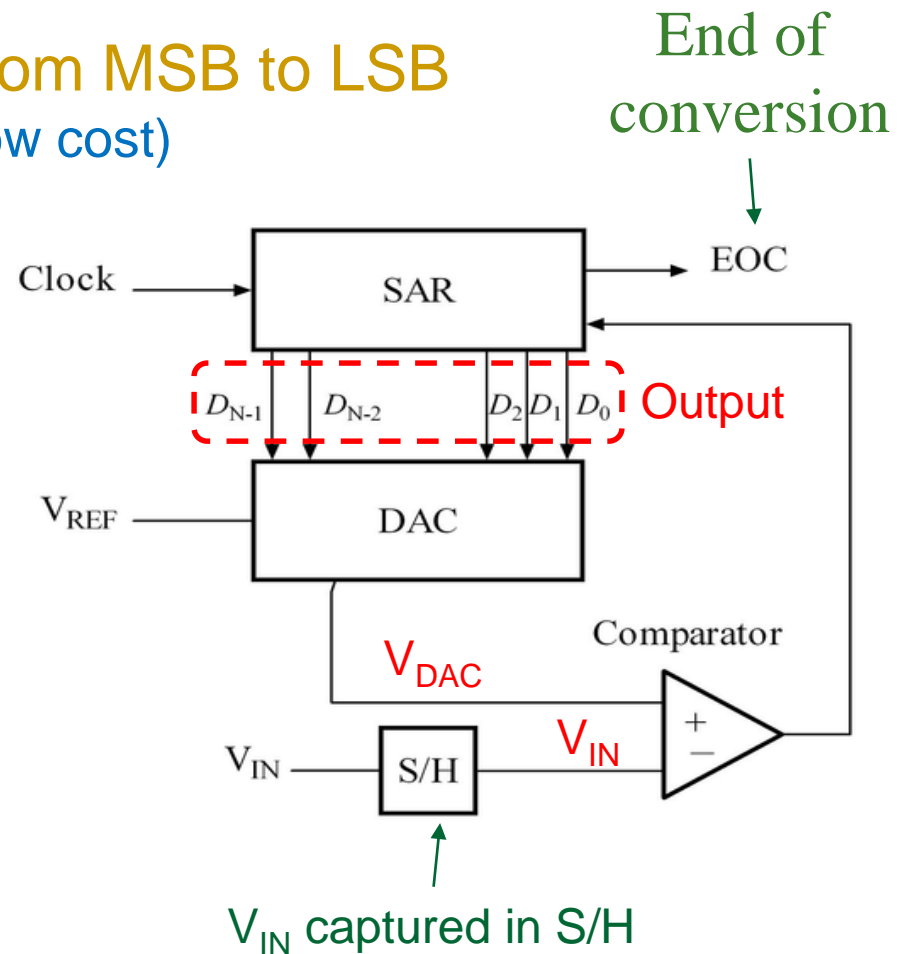


Successive approximation analog to digital converter (ADC)

- Determine one bit at a time, from MSB to LSB
Used in most microcontrollers (low cost)

- Successive Approximation Register (SAR) sets $D_{N-1} = 1$
- SAR outputs $D_{N-1} \dots D_0$, converted by DAC to analog V_{DAC}
- V_{DAC} is compared to V_{IN}
- Comparator output resets D_{N-1} to 0 in SAR if $V_{DAC} < V_{IN}$
- Repeat 1-4 for $D_{N-2} \dots D_0$ (one clock period per bit)

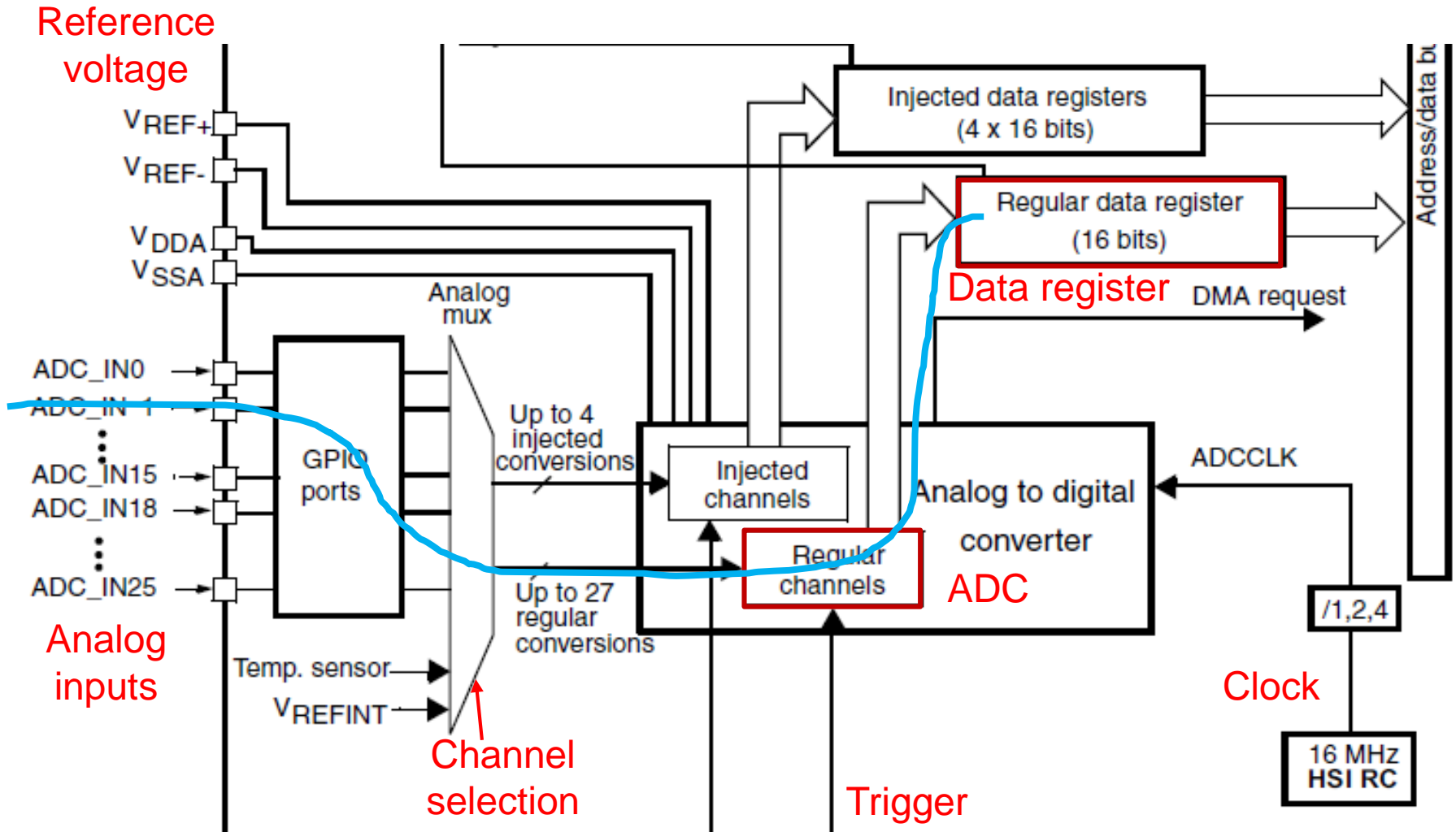
- Final SAR value $D_{N-1} \dots D_0$ is digital representation of V_{IN}



STM32L100RC Analog to Digital Converter

- Successive approximation ADC
 - Input range: $V_{REF-} \leq V_{IN} \leq V_{REF+}$ (3.6 v max)
 - Discovery Board: $V_{REF+} = VDDA$ pin, hard-wired to VDD (+3v)
 $V_{REF-} = VSSA$ pin, hard-wired to GND (0v)
 - Selectable resolution: 12, 10, 8, or 6 bits (default=12)
 - $T_{CONVERT} = 12, 11, 9, 7$ clock cycles, respectively
 - Programmable sampling time $T_{SAMPLE} = 4$ to 384 clock cycles
 - Minimum conversion time $1\mu s$ ($T_{SAMPLE} + T_{CONVERT}$)
 - 22 input channels
 - GPIO pins: ADC_IN[0:15], ADC_IN[18:21] - on designated GPIO pins
 - Temperature sensor & voltage reference: ADC_IN[16:17]
 - Single or continuous conversions
 - Scan mode for conversion of multiple channels
 - Interrupt at end of conversion or end of sequence
 - Trigger conversions with software or hardware (timers/EXTI)
-

ADC System Components



Using the ADC

- Setup
 - Connect voltage reference (hard-wired to 3v on Discovery)
 - Configure GPIO pin (select **analog mode** in MODER)
 - Enable HSI **clock** (for ADC conversion)
 - Enable ADC digital interface **clock**
 - Enable ADC
 - Select data format
 - Select sample trigger source
 - Select input channel(s)
 - Select conversion mode
 - Trigger conversion
 - Read results
 - Adjust results as needed (calibrate, average, etc.)
-

ADC initialization

- Configure GPIO pin(s) as **analog** signals
 - Refer to *Pin Definition Table* in STM32L100 data sheet to determine which GPIO pins correspond to ADC_IN0..ADC_IN21
 - Example: GPIOA pins PA0 - PA7 = ADC_IN0 - ADC_IN7, respectively
 - Enable GPIOx clock in **RCC->AHB1ENR**
 - Select analog mode in **GPIOx->MODER** (disables pull-up/down resistors)
- Enable HSI clock in **RCC->CR**, which runs ADC conversions
 - `RCC->CR |= RCC_CR_HSION;` //HSION = bit 0 of RCC->CR
- Enable ADC1 clock in **RCC->APB2ENR** (for ADC digital interface)
- Power up the ADC
 - Set ADON bit in **ADC1->CR2** (control register 2)
 - Wait until ADONS = 1 in **ADC1->SR** (takes 3.5 - 4 μsec)
 - For power efficiency, shut off the ADC when not used
- Configure ADC options (data format, conversion mode, etc.)

Data format

- 16-bit data register: ADC1->DR
 - Read as a 16-bit unsigned variable
- Data resolution can be 12, 10, 8 or 6 bits
 - Select via RES bits in **ADC1->CR1** (default RES = 00 => 12 bits)
 - 12-10-8-6 bits take 12-11-9-7 clock cycles, respectively, to convert
(trade off resolution for speed)
- Data can be left or right-aligned within the data register
 - Select via ALIGN bit in **ADC1->CR2**
 - Right alignment (ALIGN = 0):

0000ddddddddddd

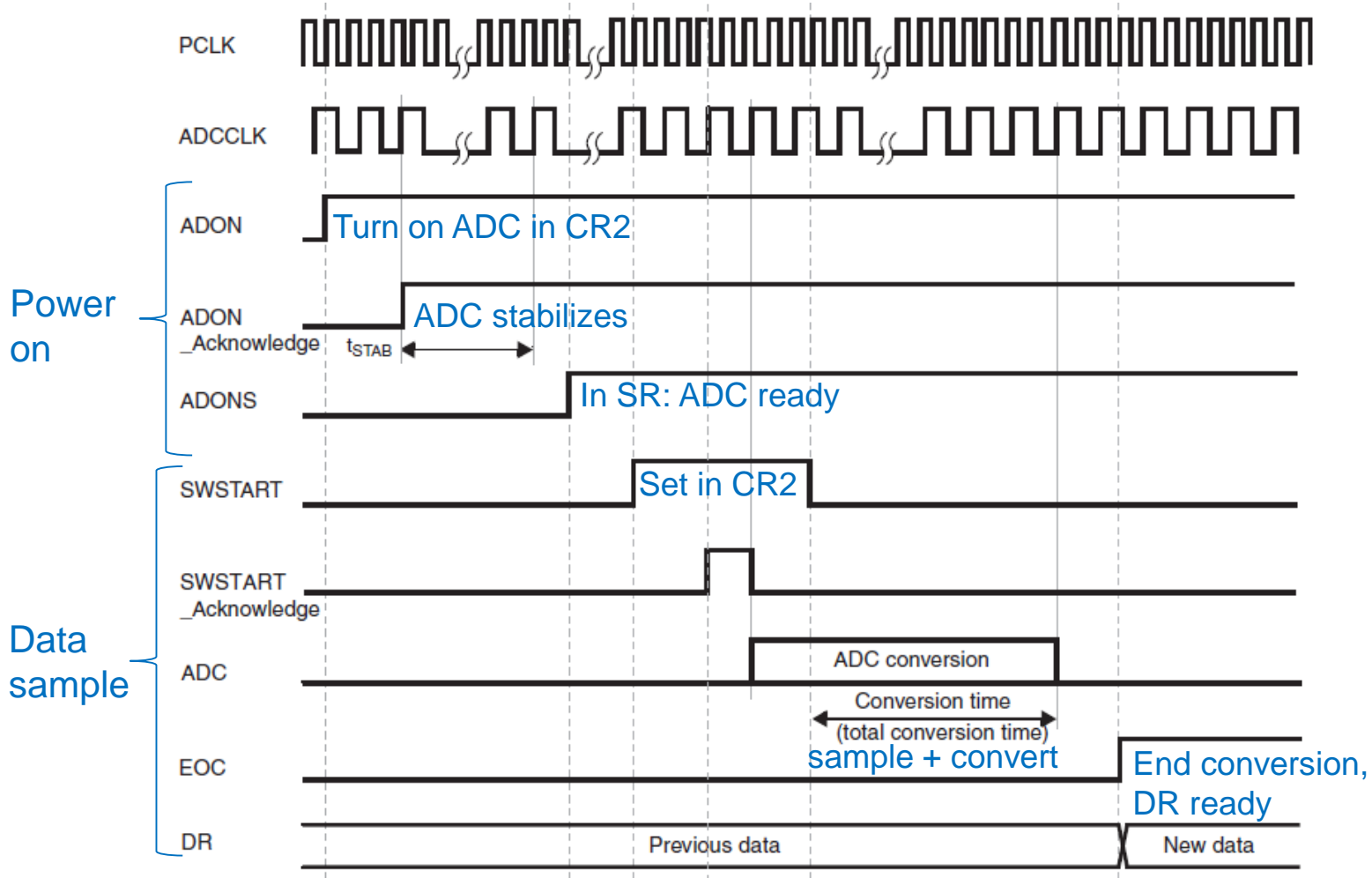
 (default)
 - Left alignment (ALIGN = 1):

ddddddddddd0000

Conversion modes

- **Single conversion** (default: `SCAN=0` in `CR1`, `CONT=0` in `CR2`)
 - Select an input channel (SQ1 field in in **ADC1->SQR5**)
 - Start the conversion (software start or hardware trigger)
 - EOC sets when conversion is complete
 - Read the result in the DR
 - **Scan mode** (enable with `SCAN=1` in `CR1`)
 - Perform a **sequence** of conversions of designated input channels
 - Define sequence length in **ADC1->SQR1**
 - Select channels in **ADC1->SQR1...ADC1->SQR5** (channels can be in any order)
 - Start the conversion *sequence* (software start or hardware trigger)
 - EOC sets after each conversion (`EOCS = 0`) or after the entire sequence is complete (`EOCS = 1`). (EOCS in **ADC1->CR2**)
 - **Continuous mode** (enable with `CONT=1` in `CR2`)
 - Start 1st conversion/sequence (software start or hardware trigger)
 - Next conversion/sequence starts automatically after a conversion/sequence completes
-

ADC timing



ADC conversion time

- Total conversion time = $T_{\text{sampling}} + T_{\text{conversion}}$
 - $T_{\text{conversion}} = 12/11/9/7$ cycles for 12/10/8/6 bit resolution
 - T_{sampling} = sampling time, ***specified for each channel***
 - Options: 4, 9, 16, 24, 48, 96, 192, 384 clock cycles
 - 3-bit value SMPn[2:0] sets sample time for channel n
 - ADC1->SMPR3 configures channels 9-0
 - ADC1->SMPR2 configures channels 19-10
 - ADC1->SMPR1 configures channels 29-20

Example: Fastest conversion rate for 12-bit data

$$f_{\text{ADCCLK}} = 16\text{MHz}; \quad \min T_{\text{sampling}} = 4; \quad \text{max res.} = 12 \text{ bits}$$

$$T_{\text{total}} = (4 + 12)/16\text{MHz} = 1\mu\text{s} \quad (1 \text{ Msamples/sec})$$

Example: Set $T_{\text{sampling}} = 24$ clock cycles for ADC_IN8

ADC1->SMPR3 (reset value = 0x00000000)

31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16
Reserved		SMP9[2:0]			SMP8[2:0]			SMP7[2:0]			SMP6[2:0]			SMP5[2:1]	
		rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw
15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
SMP5[0]	SMP4[2:0]		SMP3[2:0]			SMP2[2:0]			SMP1[2:0]			SMP0[2:0]			
rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw

SMPx[2:0]: Channel x Sample time selection (# clock cycles)

000: 4 cycles, 010: 16 cycles, 100: 48 cycles, 110: 192 cycles

010: 9 cycles, **011: 24 cycles**, 101: 96 cycles, 111: 384 cycles

Default is 4 cycles for each channel

```
// Set sample time for ADC_IN8 to 24 cycles
```

```
ADC1->SMPR3 &= ~ADC_SMPR3_SMP8; //Clear SMP8 bits*
```

```
ADC1->SMPR3 |= 0x03000000; //SMP8 = 3
```

*ADC_SMPR3_SMP8 = 0x03000000

ADC control register 1 (ADC1->CR1)

Reset value = 0x0000 0000 (bold values below)

31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	
Reserved						OVR1E	RES[1:0]		AWDEN	JAWDEN	Reserved				PDI	PDD
						rw	rw	rw	rw	rw					rw	rw
15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0	
DISCNUM[2:0]			JDISCEN	DISCEN	JAUTO	AWDSSL	SCAN	JEOCIE	AWDIE	EOCIE	AWDCH[4:0]					
rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	

RES[1:0]: resolution

- 00: 12-bit**, $T_{CONV} = 12$ cycles
- 01: 10-bit**, $T_{CONV} = 11$ cycles
- 10: 8-bit**, $T_{CONV} = 9$ cycles
- 11: 6-bit**, $T_{CONV} = 7$ cycles

SCAN: enable scan mode

- 0: disable Scan mode**
- 1: enable Scan mode**

(convert inputs selected in ADC_SQRx)

EOCIE: end of conversion interrupt enable:

- 0: disable the interrupt**
- 1: enable ADC interrupt when EOC sets**

Default setup:

- 12-bit sample
- single channel (no scan)
- no interrupt

ADC control register 2 (ADC1->CR2)

Reset value = 0x0000 0000

31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16
Res.	SWST ART	EXTEN		EXTSEL[3:0]				Res.	JSWST ART	JEXTEN		JEXTSEL[3:0]			
	rw	rw	rw	rw	rw	rw	rw		rw	rw	rw	rw	rw	rw	rw
15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Reserved				ALIGN	EOCS	DDS	DMA	Res.	DELS			Res.	ADC_C FG	CONT	ADON
				rw	rw	rw	rw		rw	rw	rw		rw	rw	rw

SWSTART: Software “start” signal
Write 1 to start conversion
 Resets when conversion starts

ADON: Turn ADC on/off
0: Disable ADC
1: Enable ADC

ALIGN: Data alignment in 16-bit result register
0: Right alignment (upper bits = 0)
1: Left alignment (lower bits = 0)

//Turn on ADC
ADC1->CR2 |= 1;

EOCS: End of conversion selection
0: EOC bit set at end of conversion sequence
1: EOC bit set at end of each conversion

CONT:
0: single conversion mode
1: continuous conversion mode

ADC status register (ADC1->SR)

31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16
Reserved															
15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Reserved						JCNR	RCNR	Res.	ADONS	OVR	STRT	JSTRT	JEOC	EOC	AWD
						r	r		r	rc_w0	rc_w0	rc_w0	rc_w0	rc_w0	rc_w0

ADONS: ADC ON state

1 = ADC ready to convert
Set/cleared by HW

EOC: End of Conversion

1 = Conversion complete (if EOCS = 0)
Sequence complete (if EOCS = 1)
Set by HW.
Clear by SW or by reading DR

```
//Wait for end of conversion (EOC=1)  
while ((ADC1->SR & 0x02) == 0);
```

Other status bits:

RCNR: Regular Channel Not Ready

1 = Regular conversion can be done
HW sets/clears

STRT: Start status

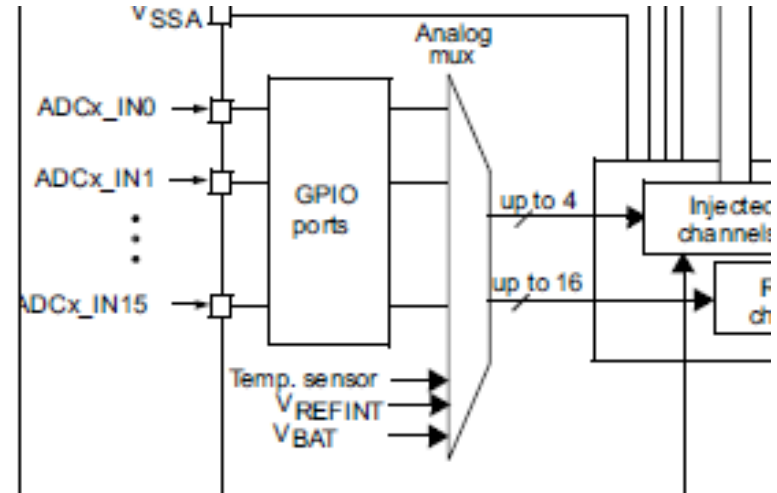
1 = Regular channel conversion
has started
HW sets/clears

OVR: Overrun detected

1 = Regular conversion data lost
(DR overwritten before read)
Clear in SW

Channel Selection

- **Sequence** of conversions (up to 28) can be done on any channel(s), in any order
- Specify #conversions in sequence via L[4:0] bits in the **ADC1->SQR1** register
 - Default is one conversion (L = 0)
- Specify channels in seq. by configuring the **ADC1_SQRx** sequence registers
 - ADC1->SQR5: conversions 1-6
 - ADC1->SQR4: conversions 7-12
 - ADC1->SQR3: conversions 13-18
 - ADC1->SQR2: conversions 19-24
 - ADC1->SQR1: conversions 25-28
 - In these registers, bits SQn[4:0] select channel # for the nth conversion in the sequence.
- For single-channel conversion, specify channel # in SQ1 of **ADC1->SQR5**



- ADC_IN16 connected to internal temperature sensor
- ADC_IN17 connected to internal reference voltage VREFINT

Example on next slide

Example: Select single conversion of ADC_IN8

ADC1->SQR1 (reset value = 0x00000000)

31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16
Reserved							L[4:0]					SQ28[4:1]			
							rw	rw	rw	rw	rw	rw	rw	rw	rw
15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
SQ28[0]	SQ27[4:0]					SQ26[4:0]					SQ25[4:0]				
rw	rw	rw	rw	rw	rw	rw	rw				rw	rw	rw	rw	rw

#conversions in the sequence = L+1 (default L=0 selects a single conversion)

ADC1->SQR1 &= ~ADC_SQR1_L; //set L=0 (ADC_SQR1_L = 0x01F00000)

(but - not really necessary, since L=0 is the default)

ADC1->SQR5 (reset value = 0x00000000)

31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16
Reserved		SQ6[4:0]					SQ5[4:0]					SQ4[4:1]			
		rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw
15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
SQ4_0	SQ3[4:0]					SQ2[4:0]					SQ1[4:0]				
rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw	rw

SQ1=x selects ADC_INx as first channel in a sequence

ADC1->SQR5 &= ~ADC_SQR5_SQ1; //clear SQ1 bits (ADC_SQR5_SQ1 = 0x0000001F)

ADC1->SQR5 |= 0x00000008; //SQ1=8 for ADC_IN8

Conversion Trigger Selection

(configure in ADC1->CR2)

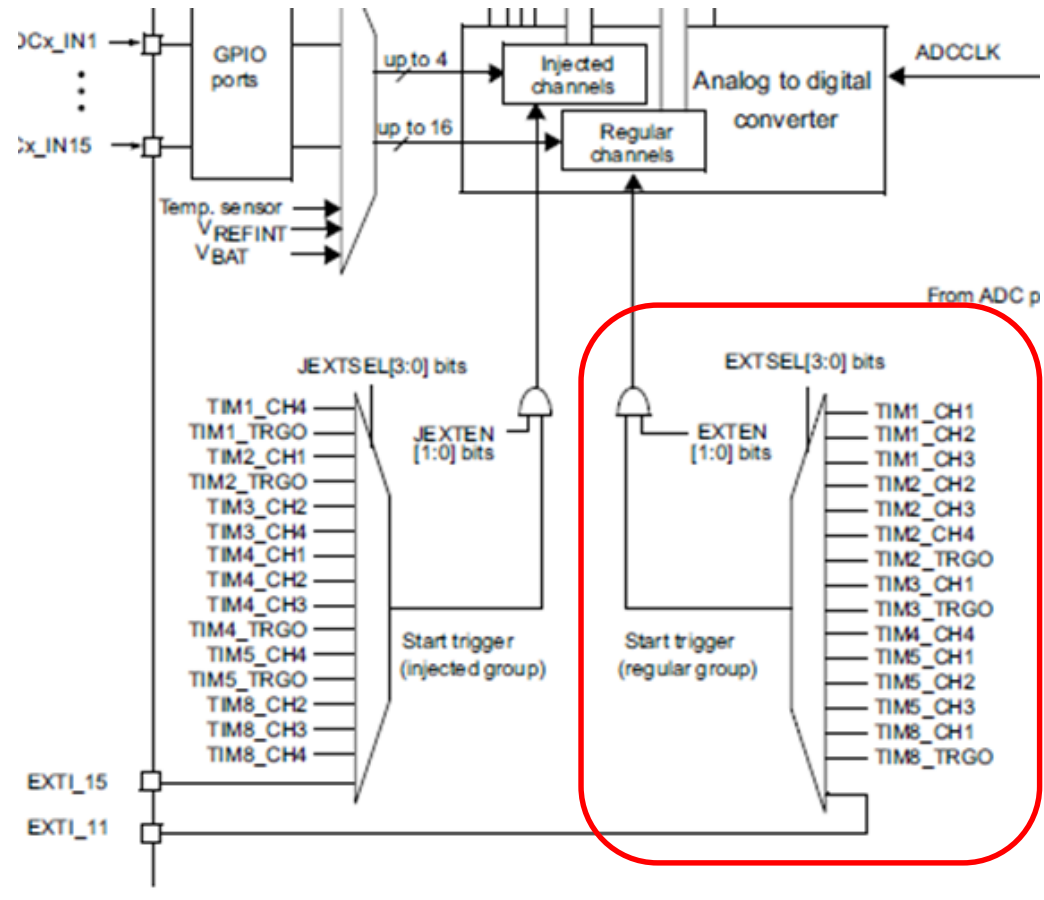
- Software trigger:

//Set SWSTART bit to 1

```
ADC->CR2 |= ADC_CR2_SWSTART;  
(0x40000000)
```

- External trigger

- Select trigger detection mode via EXTEN bits (rising and/or falling edge of trigger)
- Specify the trigger source via EXTSEL bits
Ex. EXTSEL = 0111 for TIM3_CC1 event



Using the ADC (summary)

- Setup
 - Connect voltage reference (hard-wired to 3v on Discovery)
 - Configure GPIO pin (select analog mode in MODER, turn on GPIO clk)
 - Enable HSI clock for ADC conversion (RCC->CR)
 - Enable ADC digital interface clock (RCC-<APB2ENR)
 - Power on ADC (CR2)
 - Select data format (CR1,CR2)
 - Select conversion mode (CR1,CR2)
 - Select sample time (SMPR3)
 - Select input channel(s) (SQR1,SQR5)
 - Trigger conversion (Software: CR2, or External: CR2)
 - Read results (DR)
 - Adjust results as needed (calibrate, average, etc.)
-

Working with ADC data samples

$$ADC1 \rightarrow DR = \frac{V_{in}}{V_{ref}} \times 2^{\#bits}$$

- Several conversions may be needed
 - Average several samples of N to filter out noise
 - Compute approximate input voltage V_{in} from N
 - For a sensor, use sensor's transfer function to compute the physical parameter value (e.g. pressure) from V_{in}
 - Do additional computations based on this physical parameter (e.g. compute depth based on pressure)
 - Convert data to some other form (eg. ASCII characters, to send to a display)
- Numeric considerations
 - Consider resolution of measured data (eg. 12 bits) vs resolution of other data involved in calculations
 - Consider measurement errors in the ADC
 - Some program data may be in floating-point format

Lab Procedure

- Design and incorporate a **rectifier & filter** into your circuit to convert the tachometer output to a DC voltage level
 - Model in PSPICE to verify design.
 - Measure tachometer signal and rectifier/filter output with o'scope.
 - EEBoard waveform generator can be used to test the circuit without the motor.
- Modify software to add **ADC initialization** function and **ADC input** function (trigger conversion, wait for EOC, read result)
 - Consider averaging some # of samples
 - EEBoard waveform generator can be used to test the circuit without the motor.
- Measure: tachometer signal amplitude, rectifier/filter voltage output & ADC value for each of the 10 speed settings
- Plot:
 - ADC value vs tachometer output amplitude
 - ADC value vs. ATD input voltage (rectifier/filter output)
 - ADC value vs. PWM signal duty cycle